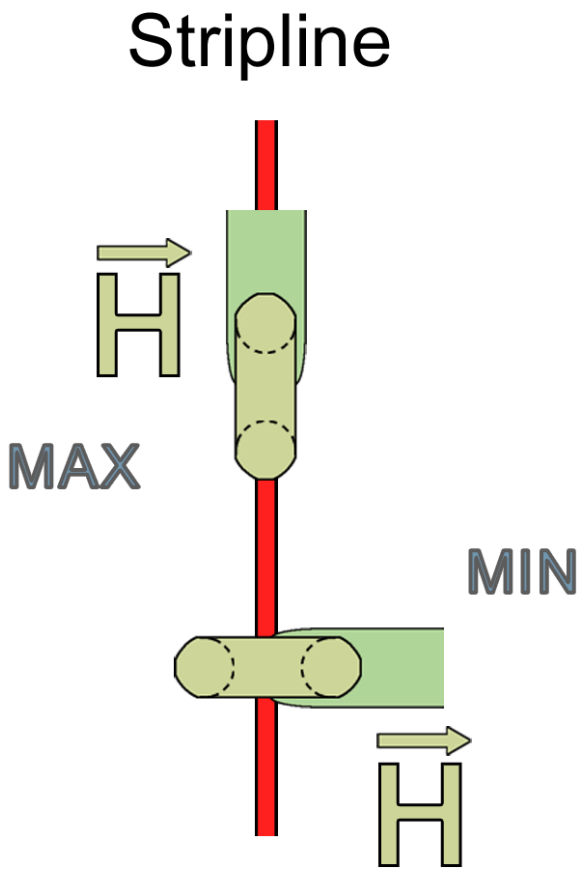
ICR HV Product Family

Near-Field Microprobes up to 6 GHz



Short description

The near-field microprobe is designed for high resolution measurement of magnetic near fields. With the ICR RF probes the following measurements can be done:

-Surface Scan via IC according to IEC 61967-3
-Volumenscan via IC
-PIN-Scan

The measuring coil within the ICR RF probe head is vertically aligned with the measurement surface.
A preamplifier is integrated into the probe casing and powered by the Bias-Tee.
The ICR near field probes undergo a quality check before they are delivered.

The measuring coil in the ICR -RF probe heads is positioned vertically to the measuring surface. A preamplifier is integrated into the probe casing and is powered by the Bias-Tee.
The ICR near field micro probes undergo a quality check before they are delivered. Different reference setup measurements are performed and a calibration curve is generated. Three different calibration curves are determined:

1)standardized calibration curve
2)H-field calibration curve
3)current calibration curve

Attention: Due to its construction, the ICR probe is sensitive to shock and the delivery includes shipping and handling protection.

Technical parameters

Frequency range	(0.5 ... 6) GHz
Resolution	(60 ... 300) µm